

NOTES:

1. SUBSTRATE MATERIAL:
FUSED SILICA
2. CLEAR APERTURE AND COATING APERTURE
ARE CENTERED ON SURFACE
3. COATING (APPLY ACROSS CLEAR APERTURE)
S1: $R_s(ABS) > 99.8\%$ AT 532nm AT 45° AOI
 $R(AVG) > 99.5\%$ FROM 523-533nm AT 45° AOI
DAMAGE THRESHOLD,
PULSED: 10 J/cm², 20 ns, 20 Hz @ 532 nm
CW: 500 kW/cm² @ 1064 nm

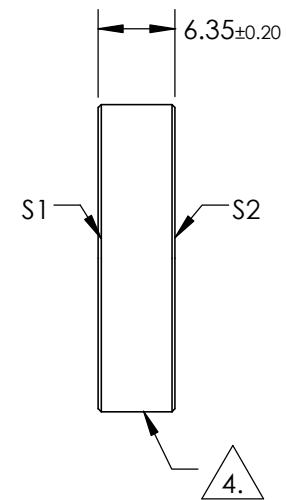
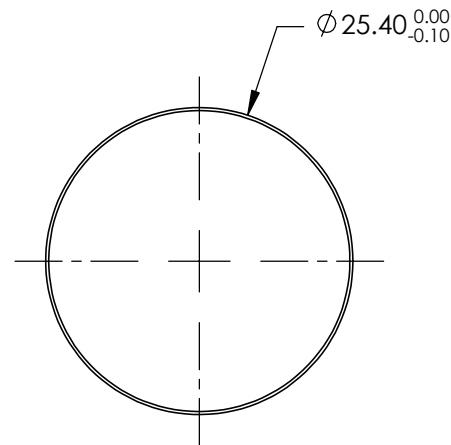
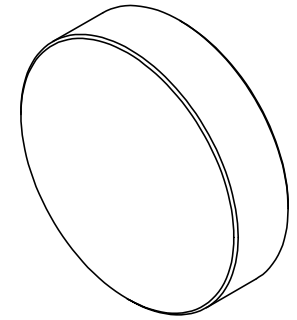
S2:NONE

4. FINE GRIND SURFACE


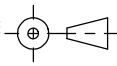
5. SURFACE FLATNESS AND SURFACE QUALITY
SPECIFICATIONS APPLY ACROSS CLEAR APERTURE

6. RoHS: COMPLIANT

**FOR INFORMATION ONLY:
DO NOT MANUFACTURE
PARTS TO THIS DRAWING**



SPECIFICATIONS SUBJECT TO CHANGE WITHOUT NOTICE
DIMENSIONS ARE FOR REFERENCE ONLY

REV. A	S1	S2	 Edmund Optics®			
SHAPE	PLANO	PLANO				
SURFACE FLATNESS	0.1 WAVE	N/A		TITLE	Ø25.4mm, 532nm, Nd-YAG LASER LINE MIRROR (STANDARD)	
SURFACE QUALITY	10 - 5	N/A		DWG NO	34825	SHEET 1 OF 1
CLEAR APERTURE	Ø21.59	Ø21.59		ALL DIMS IN	mm	
BEVEL	PROTECTIVE AS NEEDED	PROTECTIVE AS NEEDED				